

PJD30N04S-AU **40V N-Channel Enhancement Mode MOSFET TO-252AA** 40 V Current 43 A Voltage **Features** • Rds(ON), Vgs@10V, Id@20A<10.6mΩ • Rds(ON), Vgs@4.5V, Id@10A<14.6mΩ • Excellent FOM • Logic Level Drive • AEC-Q101 qualified 2 Drain • Lead free in compliance with EU RoHS 2.0 • Green molding compound as per IEC 61249 standard (1) Gate **Mechanical Data** • Case : TO-252AA Package Source • Terminals : Solderable per MIL-STD-750, Method 2026 • Approx. Weight : 0.3217 grams

### Maximum Ratings and Thermal Characteristics (T<sub>A</sub>=25°C unless otherwise noted)

PARAMETE	R	SYMBOL	LIMIT	UNITS
Drain-Source Voltage		V <sub>DS</sub>	40	V
Gate-Source Voltage		V <sub>GS</sub>	±20	
Continuous Drain Current <sup>(Note 3)</sup>	T <sub>C</sub> =25°C		43	
	T <sub>c</sub> =100 <sup>°</sup> C	I <sub>D</sub>	31	А
Pulsed Drain Current <sup>(Note 1)</sup>	T <sub>C</sub> =25°C	I <sub>DM</sub>	172	
Power Dissipation	T <sub>C</sub> =25°C	<b>D</b> _	36	10/
	Tc=100°C	Po	18	W
Continuous Drain Current <sup>(Note 4)</sup>	T <sub>A</sub> =25°C		12.5	
	T <sub>A</sub> =70 <sup>°</sup> C	ID	10.5	A
Power Dissipation	T <sub>A</sub> =25°C	6	3	
	T <sub>A</sub> =70°C	Po	2.1	W
Single Pulse Avalanche Energy <sup>(Note 5)</sup>		Eas	20	mJ
Operating Junction and Storage Temperature Range		TJ,T <sub>STG</sub>	-55~175	°C
Thermal Resistance <sup>(Note 4)</sup>	Junction to Case	R <sub>θJC</sub>	4.2	°C/W
	Junction to Ambient	R <sub>θJA</sub>	50	C/VV



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#### Electrical Characteristics (TA=25°C unless otherwise noted)

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNITS	
Static						•	
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	40	-	-	V	
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS}=V_{GS}$ , $I_{D}=50uA$	1.1	1.6	2.3		
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =20A	-	8.3	10.6	mΩ	
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =10A	-	11.2	14.6		
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =40V, V <sub>GS</sub> =0V	-	-	±1	uA	
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	-	-	±10	uA	
		V <sub>GS</sub> =±10V, VDS=0V	-	-	±1		
Dynamic <sup>(Note 6)</sup>							
Total Gate Charge	Qg	$V_{DS}=32V, I_{D}=20A,$	-	13	-	nC	
Gate-Source Charge	Qgs		-	3	-		
Gate-Drain Charge	Q <sub>gd</sub>	V <sub>GS</sub> =10V	-	2	-		
Input Capacitance	Ciss	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V,	-	744	-	pF	
Output Capacitance	Coss		-	159	-		
Reverse Transfer Capacitance	Crss	f=1MHz	-	29	-		
Gate resistance	Rg	f=1MHz	-	1.6	-	Ω	
Turn-On Delay Time	td <sub>(on)</sub>	V <sub>DS</sub> =32V, I <sub>D</sub> =20A, V <sub>GS</sub> =10V, R <sub>G</sub> =3Ω	-	9	-	ns	
Turn-On Rise Time	tr		-	3	-		
Turn-Off Delay Time	td <sub>(off)</sub>		-	21	-		
Turn-Off Fall Time	tf		-	3	-		
Drain-Source Diode							
Diode Forward Current	I <sub>S</sub>	T 05°0	-	-	43	A	
Pulsed Diode Forward Current	I <sub>SM</sub>	Tc=25°C	_	-	172		
Diode Forward Voltage	V <sub>SD</sub>	Is=20A, V <sub>GS</sub> =0V	-	0.9	1.3	V	
Reverse Recovery Time	Trr	V <sub>GS</sub> =0V, I <sub>S</sub> =20A	-	21	-	ns	
Reverse Recovery Charge	Qrr	dls/dt=100A/us	-	10	-	nC	

NOTES :

- 1. Pulse width <100us, Duty cycle <2%.
- 2. Essentially independent of operating temperature typical characteristics.
- 3. Chip capability with an  $R_{\theta JC}$ =4.2°C/W.
- 4.  $R_{\theta JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. Mounted on a 1 inch<sup>2</sup> with 2oz.square pad of copper.
- 5. The test condition is L=0.5mH,  $I_{AS}$ =9A,  $V_{DD}$ =30V,  $V_{GS}$ =10V, Starting T\_J=25°C. the chip is about to carry  $I_{AS}$ ≈18A.
- 6. Guaranteed by design, not subject to production testing.

SEMI CONDUCTOR

PAN

## PJD30N04S-AU

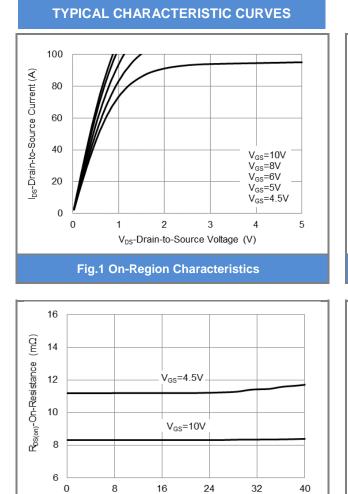
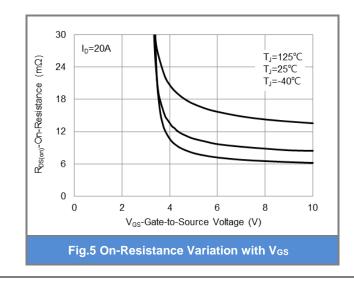
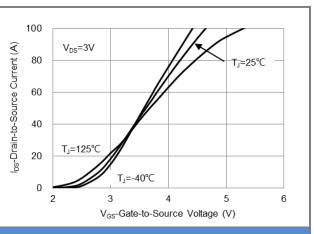


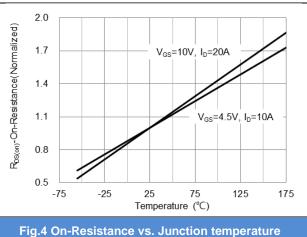
Fig.3 On-Resistance vs. Drain Current

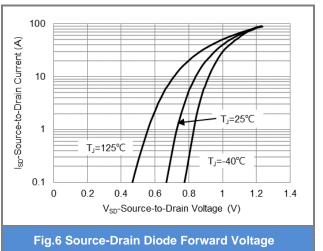
IDS-Drain-to-Source Current (A)





**Fig.2 Transfer Characteristics** 

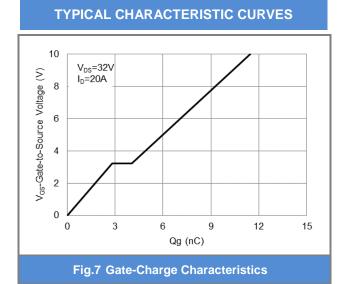




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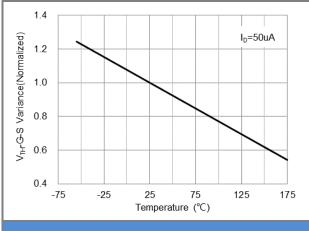
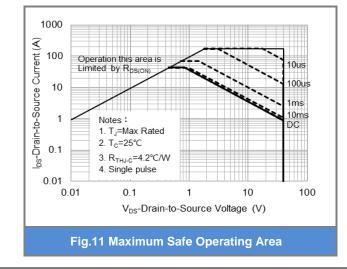
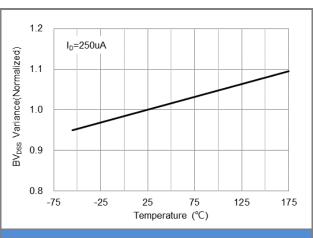


Fig.9 Threshold Voltage Variation with Temperature







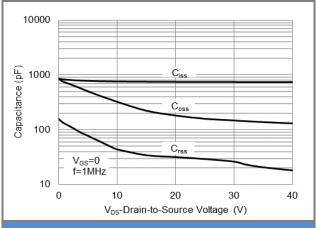
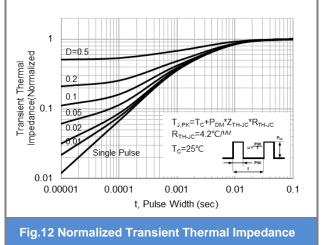


Fig.10 Capacitance vs. Drain-Source Voltage



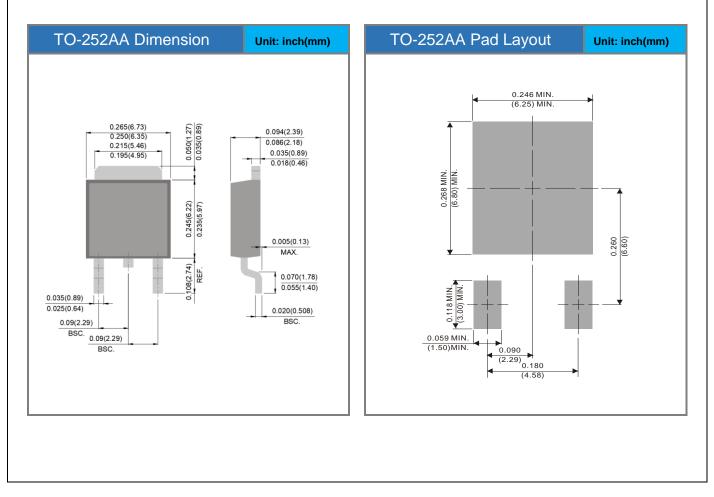


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#### **Product and Packing Information**

Part No.	Package Type	Packing Type	Marking
PJD30N04S-AU	TO-252AA	3K pcs / 13" reel	D30N04S

### Packaging Information & Mounting Pad Layout





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